漂移电压基准

查询样品: REF3325-DIE

特性

- 低电源电流
- 高输出电流
- 低温度漂移
- 高初始精度

应用范围

- 便携式设备
- 数据采集系统
- 医疗设备
- 测试设备

说明

REF3325 是一款低功耗、高精度、低压降电压基准。 小尺寸和低功耗使 REF3325 成为多种便携式和电池供电类应用的理想选择。

ORDERING INFORMATION(1)

PRODUCT	PACKAGE DESIGNATOR	PACKAGE(2)	ORDERABLE PART NUMBER	PACKAGE QUANTITY
REF3325	TD	Bare die in waffle pack	REF3325ATDD1	400
			REF3325ATDD2	10

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Processing is per the Texas Instruments commercial production baseline and is in compliance with the Texas Instruments Quality Control System in effect at the time of manufacture. Electrical screening consists of DC parametric and functional testing at room temperature only. Unless otherwise specified by Texas Instruments AC performance and performance over temperature is not warranted. Visual Inspection is performed in accordance with MIL-STD-883 Test Method 2010 Condition B at 75X minimum.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

BARE DIE INFORMATION

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
15 mils.	Silicon with backgrind	Floating	TiW/AlCu (0.5%)	1100 nm

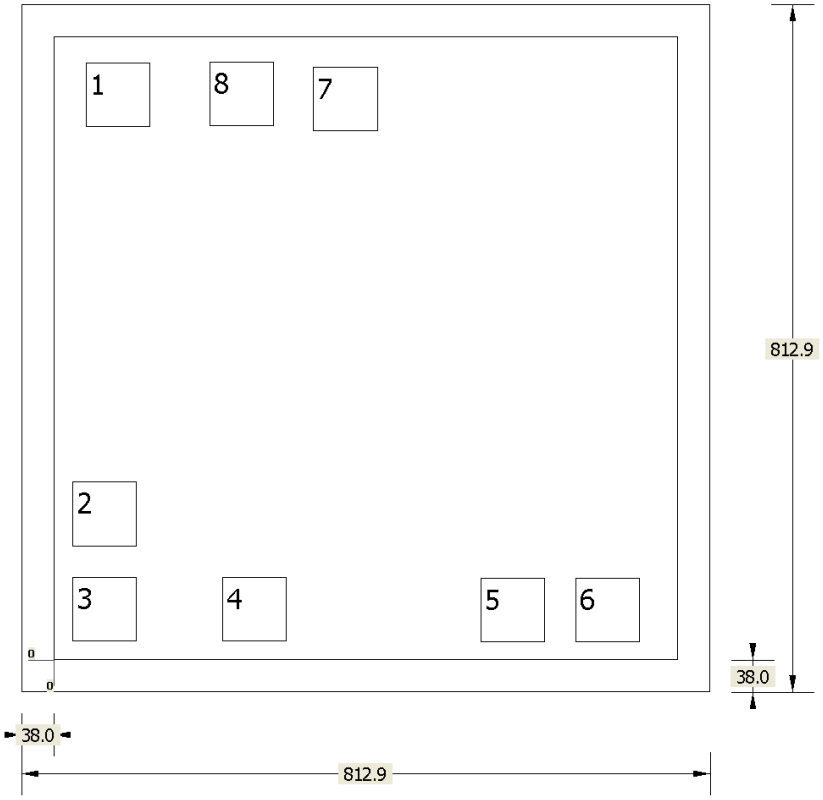


Table 1. Bond Pad Coordinates in Microns(1)

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
IN	1	38	629.6	114	705.6
N/C	2	22	134.5	98.15	210.65
N/C	3	22	22.1	98.15	98.25
N/C	4	199.25	22.1	275.4	98.25
OUT	5	504.15	21.3	580.15	97.3
OUT	6	616.35	21.3	692.35	97.3
GND	7	306.4	625.1	382.55	701.25
GND	8	183.8	630.65	259.95	706.8

(1) Substrate N/C.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
REF3325ATDD1	ACTIVE			0	400	RoHS & Green	Call TI	N / A for Pkg Type	0 to 70		Samples
REF3325ATDD2	ACTIVE			0	10	RoHS & Green	Call TI	N / A for Pkg Type	0 to 70		Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
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Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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